JETIR.ORG

ISSN: 2349-5162 | ESTD Year: 2014 | Monthly Issue



JOURNAL OF EMERGING TECHNOLOGIES AND INNOVATIVE RESEARCH (JETIR)

An International Scholarly Open Access, Peer-reviewed, Refereed Journal

Ref No : JETIR / Vol 7 / Issue 12 / 093

Confirmation Letter

To,

Rajesh Agrawal

Published in : Volume 7 | Issue 12 | 2020-12-11



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

About JETIR : An International Scholarly Open Access Journal, Peer-Reviewed, Refereed

> Journal Impact Factor Calculate by Google Scholar and Semantic Scholar AI-Powered Research Tool, Multidisciplinary, Monthly, Multilanguage Journal Indexing in All Major Database & Metadata, Citation Generator, Impact Factor:

7.95, ISSN: 2349-5162

UGC Approval: UGC and ISSN Approved - UGC Approved Journal No: 63975 | Link:

https://www.ugc.ac.in/journallist/subjectwisejurnallist.aspx?tid=MjM0OTUxNjI

=&&did=U2VhcmNoIGJ5IElTU04=

Registration ID: JETIR 303956 Paper ID : JETIR2012093

Title of Paper : An Implementation of Fraudulent URL Detection with Advanced Feature and

ML Technique

Impact Factor : 7.95 (Calculate by Google Scholar)

DOI

: Volume 7 | Issue 12 | 2020-12-11 Published in

Publication Date: 2020-12-11 Page No : 731-735

Published URL: http://www.jetir.org/view?paper=JETIR2012093

: Rajesh Agrawal, Sourabh Kumbhar

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.















International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162)

www.jetir.org | editor@jetir.org | Impact Factor: 7.95 (Calculate by Google Scholar)

An International Scholarly Open Access Journal, Peer-Reviewed, Refereed Journal